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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/006,605	SMITH ET AL.	
Examiner	Art Unit	
Merilyn P. Nguyen	2161	

SEARCHED			
Class	Subclass	Date	Examiner
707	1,2,4,5,8,1 0,100,102, 201,203	03/19/2006	MN
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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